

**Notice of References Cited**

Application/Control No.

09/842,139

Applicant(s)/Patent Under  
Reexamination  
TAKESHIMA ET AL.

Examiner

Brian E. Miller

Art Unit

2652

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0008669	07-2001	Hara et al.	428/64.4
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11-134717	05-1999	Japan	Hidemi et al	---
	O	JP 2000-57635	02-2000	Japan	Fujio et al	---
	P	JP 09-245379	09-1997	Japan	Shinichi et al	---
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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